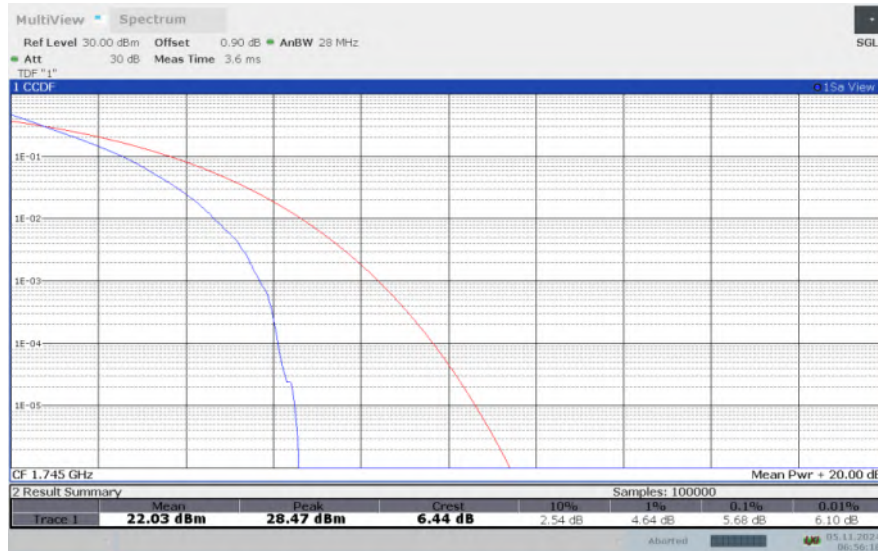


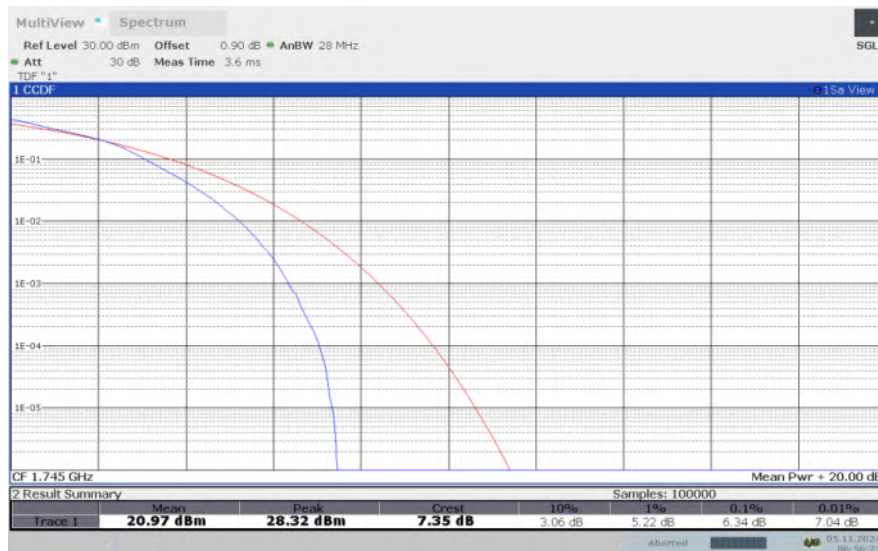
LTE Band 66, 15MHz

Frequency (MHz)	RB	PAPR (dB)		
		QPSK	16QAM	64QAM
1745	100%,0	5.68	6.34	6.60

LTE band 66 , 15MHz Bandwidth,QPSK



LTE band 66 , 15MHz Bandwidth,16QAM



LTE band 66 , 15MHz Bandwidth,64QAM



LTE Band 66, 20MHz

Frequency (MHz)	RB	PAPR (dB)		
		QPSK	16QAM	64QAM
1745	100%,0	5.48	6.36	6.64

LTE band 66 , 20MHz Bandwidth,QPSK



LTE band 66 , 20MHz Bandwidth,16QAM



LTE band 66 , 20MHz Bandwidth,64QAM



LTE Band 71, 5MHz

Frequency (MHz)	RB	PAPR (dB)		
		QPSK	16QAM	64QAM
680.5	100%,0	5.58	6.36	6.74

LTE band 71 , 5MHz Bandwidth,QPSK



LTE band 71 , 5MHz Bandwidth,16QAM



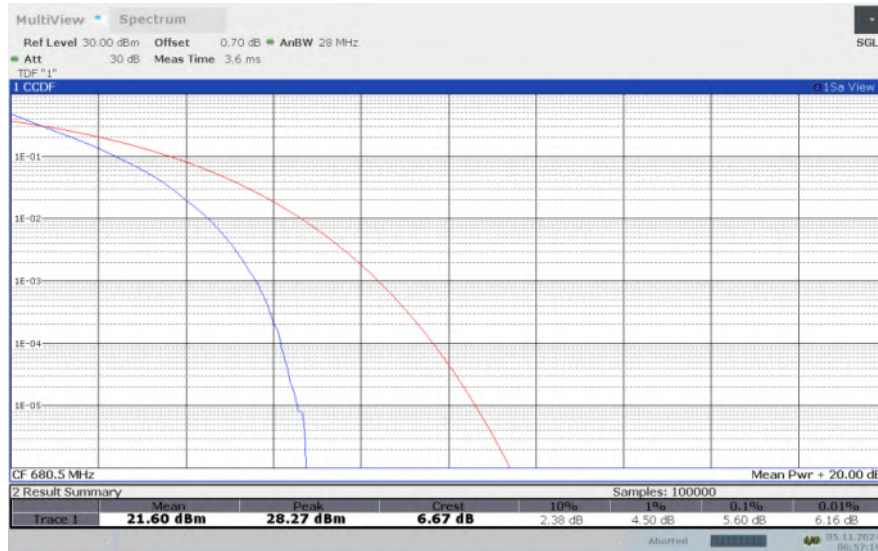
LTE band 71 , 5MHz Bandwidth,64QAM



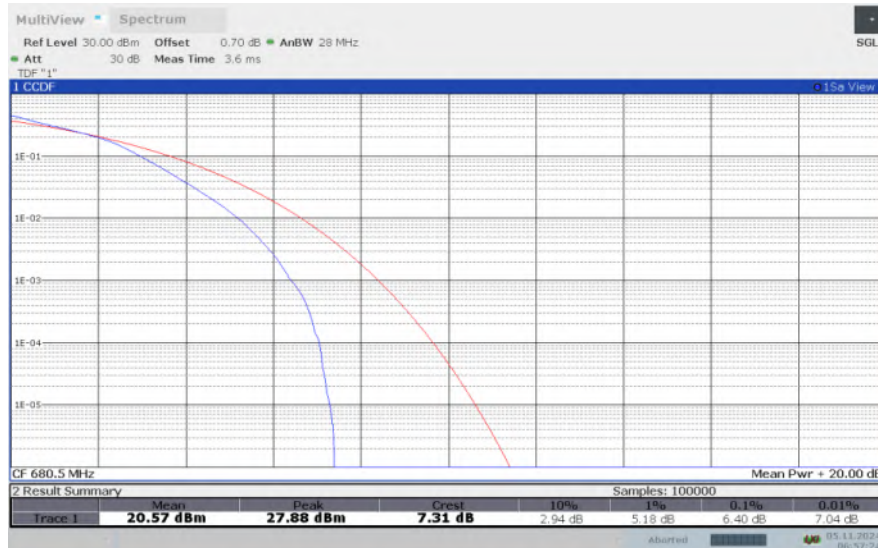
LTE Band 71, 10MHz

Frequency (MHz)	RB	PAPR (dB)		
		QPSK	16QAM	64QAM
680.5	100%,0	5.60	6.40	6.70

LTE band 71 , 10MHz Bandwidth,QPSK



LTE band 71 , 10MHz Bandwidth,16QAM



LTE band 71 , 10MHz Bandwidth,64QAM



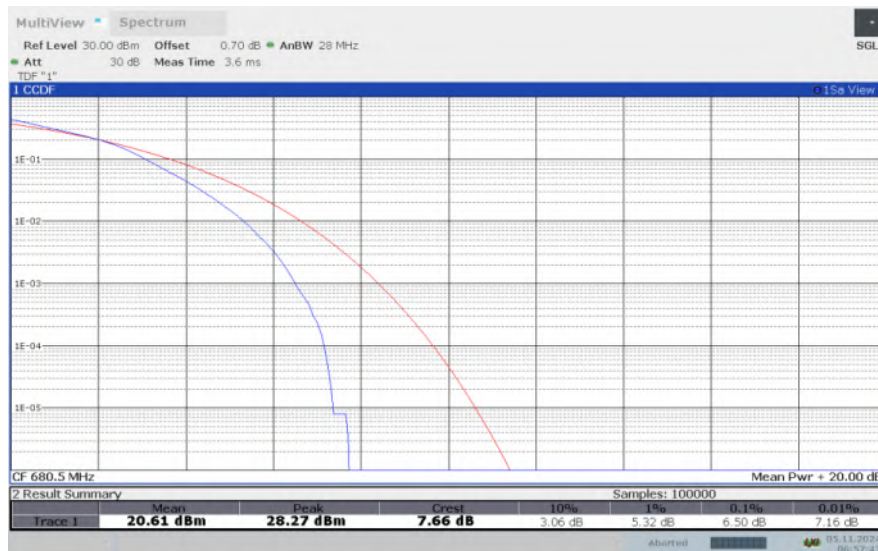
LTE Band 71, 15MHz

Frequency (MHz)	RB	PAPR (dB)		
		QPSK	16QAM	64QAM
680.5	100%,0	5.92	6.50	6.66

LTE band 71 , 15MHz Bandwidth,QPSK

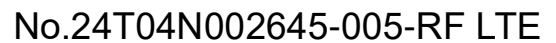


LTE band 71 , 15MHz Bandwidth,16QAM



LTE band 71 , 15MHz Bandwidth,64QAM





Frequency (MHz)	RB	PAPR (dB)		
		QPSK	16QAM	64QAM
683	100%,0	5.72	6.54	6.80

MultiView Spectrum

Ref Level 30.00 dBm Offset 0.70 dB AnBW 28 MHz

Att 30 dB Meas Time 3.6 ms

TDF "1"

1 CCDF 15s View

CF 683.0 MHz Mean Pwr + 20.00 dB

2 Result Summary Samples: 100000

	Mean	Peak	Crest	10%	1%	0.1%	0.01%
Trace 1	21.53 dBm	28.82 dBm	7.30 dB	2.40 dB	4.54 dB	5.72 dB	6.38 dB

Aborted 03.11.2023 06:58

MultiView ☒ Spectrum

Ref Level 30.00 dBm Offset 0.70 dB AnBW 28 MHz

Att 30 dB Meas Time 3.6 ms

TDF "1"

1 CCDF 15a View

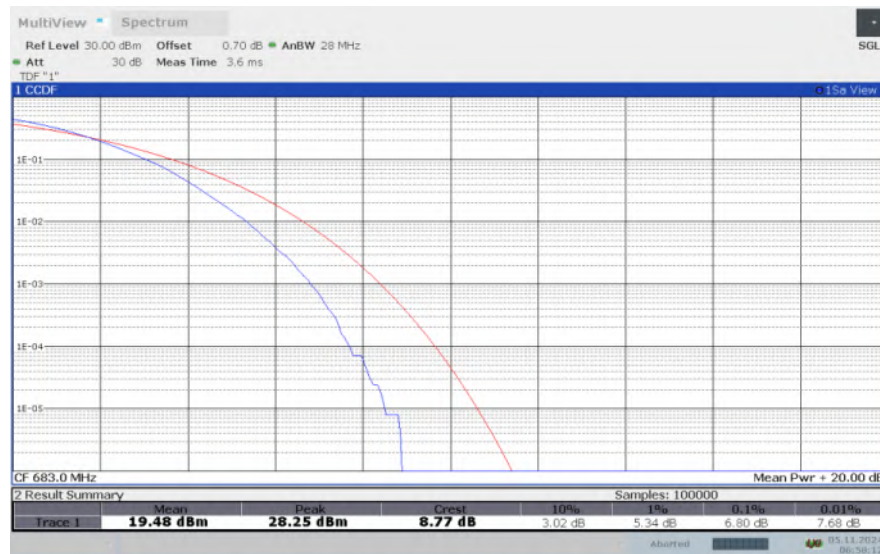
CF 683.0 MHz Mean Pwr + 20.00 dB

2 Result Summary

	Mean	Peak	Crest	10%	1%	0.1%	0.01%
Trace 1	20.41 dBm	28.33 dBm	7.92 dB	2.96 dB	5.18 dB	6.54 dB	7.38 dB

Aborted 05.11.2018 05:56:48

LTE band 71 , 20MHz Bandwidth,64QAM



Note: Expanded measurement uncertainty is $U = 0.48$, $k = 2$

ANNEX B: Accreditation Certificate

Accredited Laboratory

A2LA has accredited

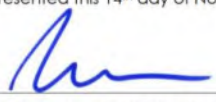
SHENZHEN ACADEMY OF INFORMATION AND COMMUNICATIONS TECHNOLOGY
Shenzhen, People's Republic of China

for technical competence in the field of
Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 General requirements for the competence of testing and calibration laboratories. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 14th day of November 2023.



Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 4353.01
Valid to November 30, 2025

For the tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.

*****END OF REPORT*****